

Device Modeling Report

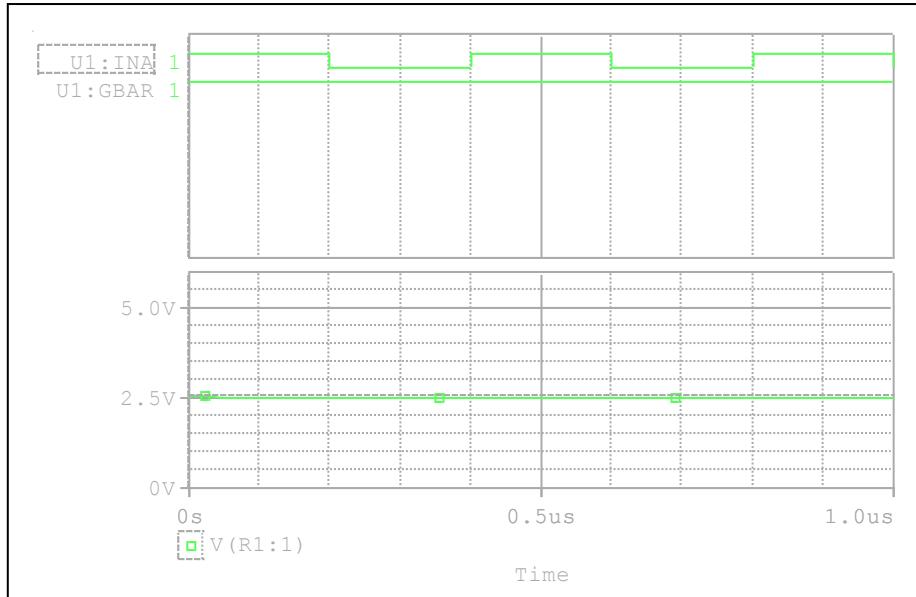
COMPONENTS : CMOS DIGITAL INTEGRATED CIRCUIT
PART NUMBER : TC7SZ125F
MANUFACTURER : TOSHIBA



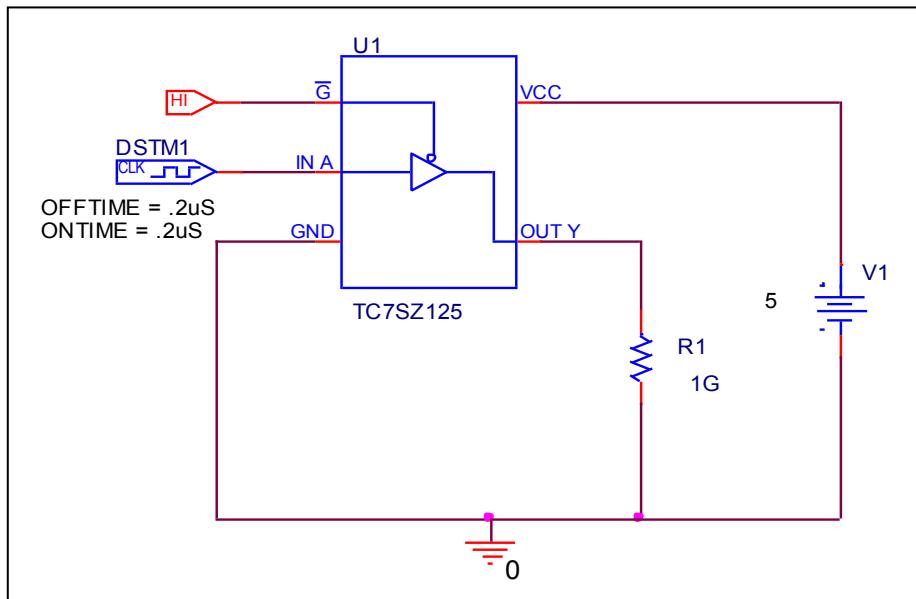
Bee Technologies Inc.

Truth Table

Circuit simulation result



Evaluation circuit

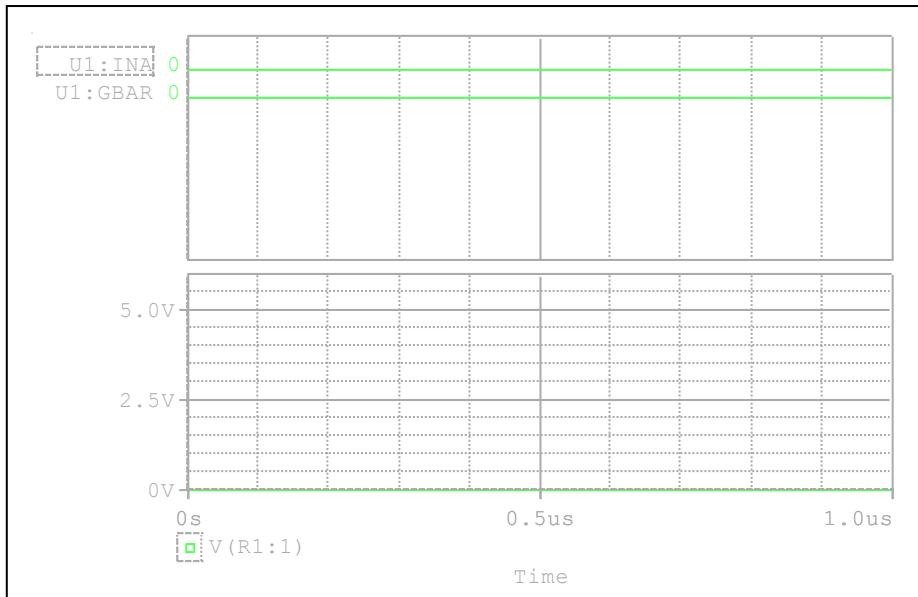


Comparison table

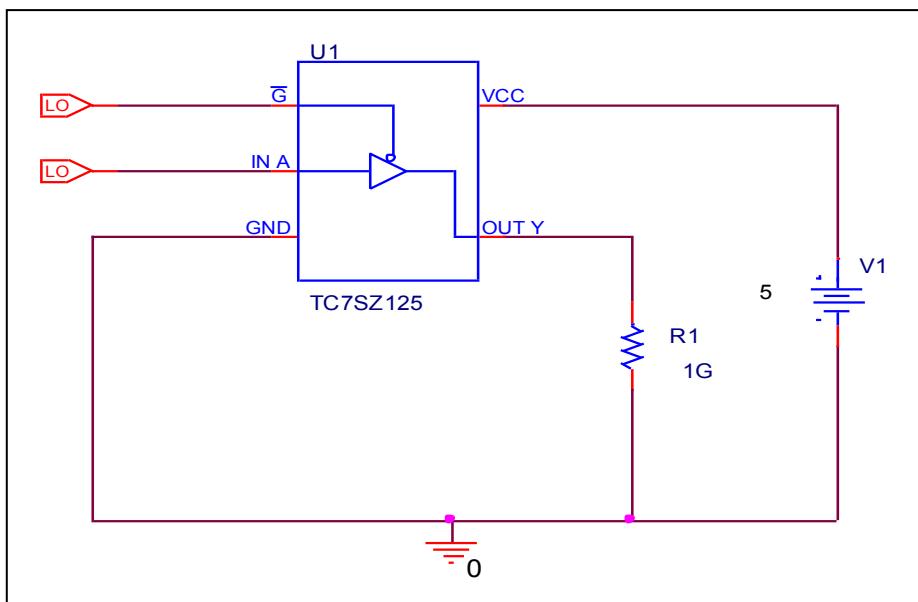
Input		Output		%Error
A	\bar{G}	Y (Measurement)	Y (Simulation)	
X	H	Z	Z	0

Truth Table

Circuit simulation result



Evaluation circuit

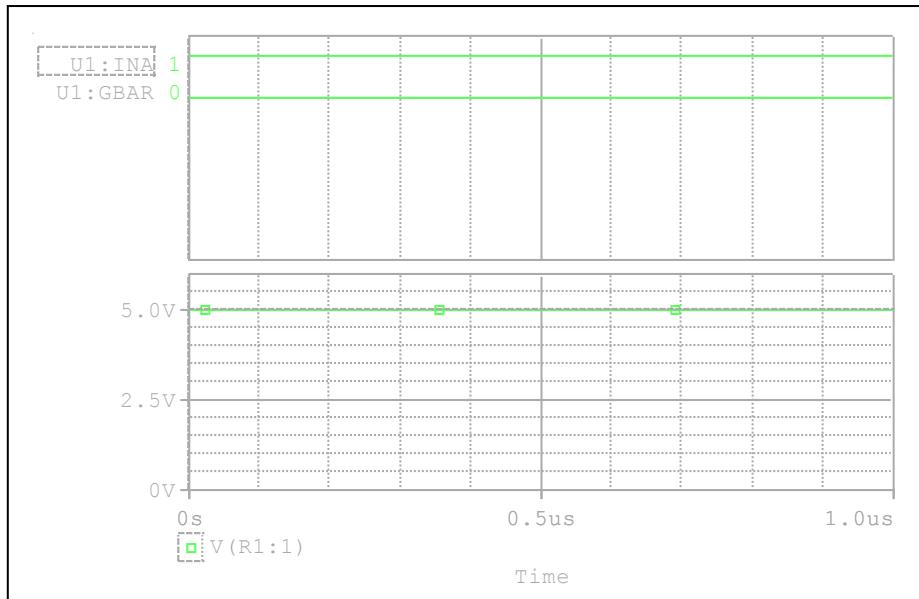


Comparison table

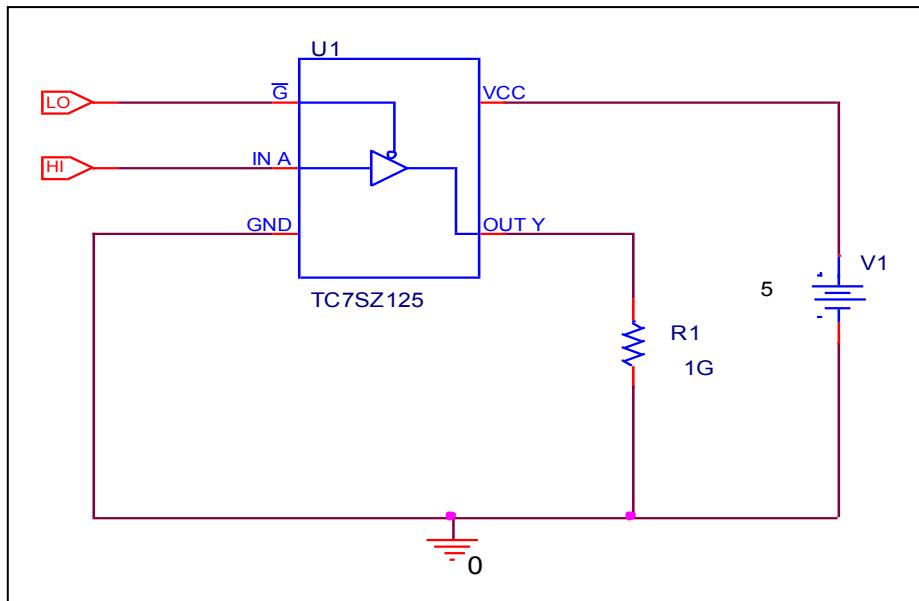
Input		Output		%Error
A	G̅	Y (Measurement)	Y (Simulation)	
L	L	L	L	0

Truth Table

Circuit simulation result



Evaluation circuit

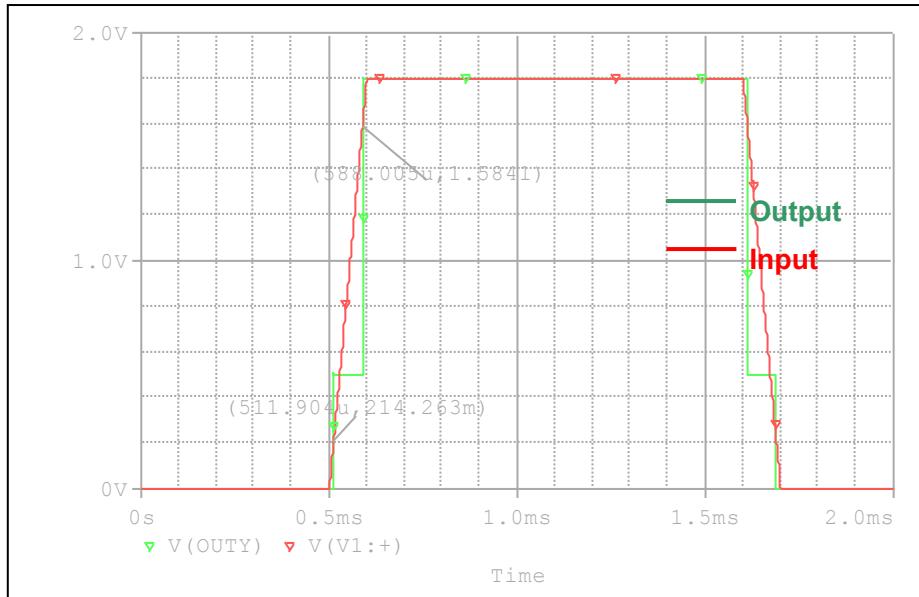


Comparison table

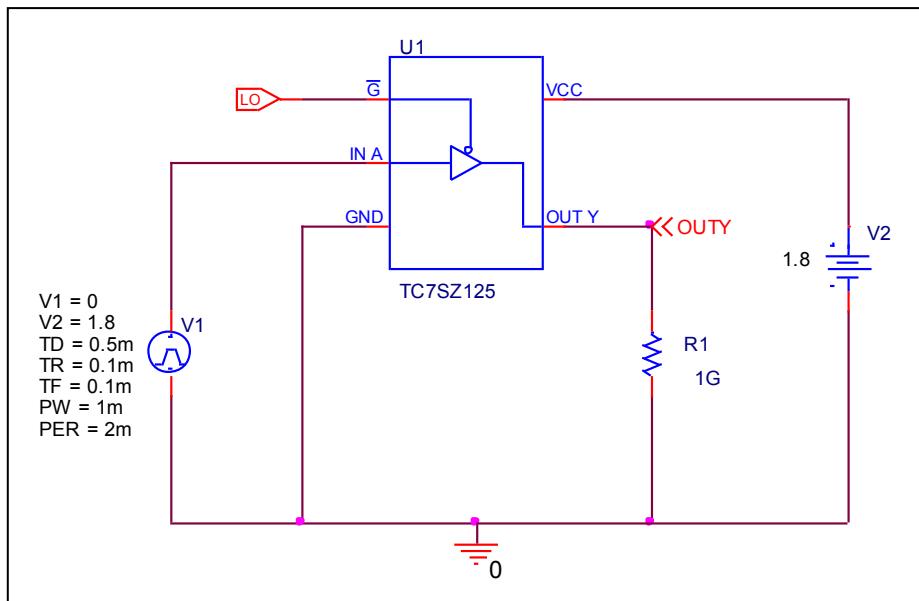
Input		Output		%Error
A	G̅	Y (Measurement)	Y (Simulation)	
H	L	H	H	0

High Level and Low Level Input Voltage ($V_{cc} = 1.8 \text{ V}$)

Circuit simulation result



Evaluation circuit

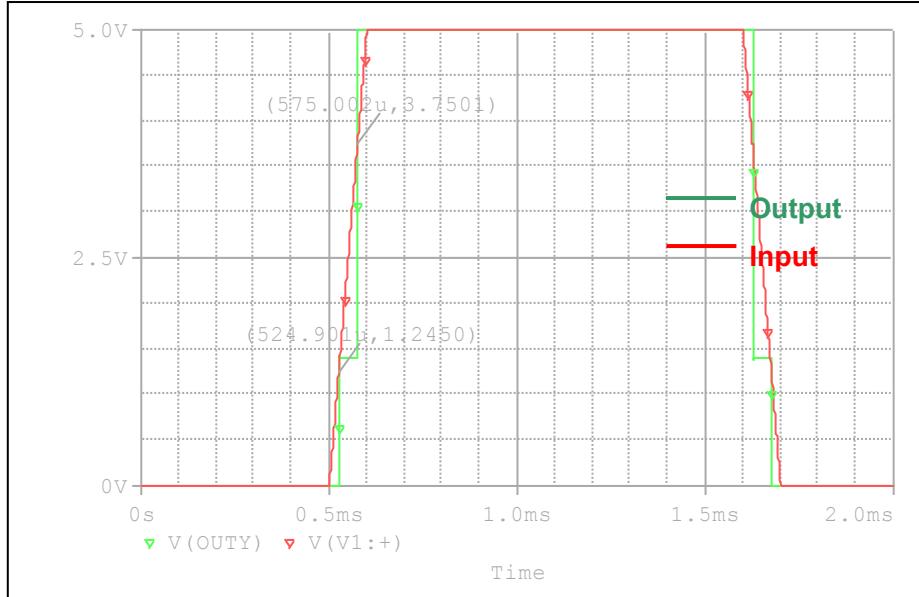


Comparison table

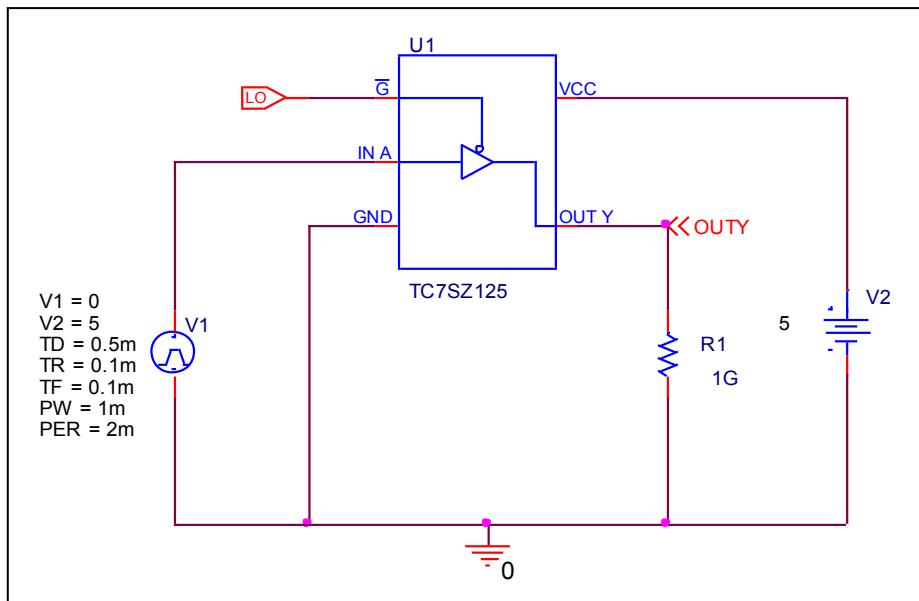
$V_{cc} = 1.8\text{V}$	Measurement	Simulation	%Error
$\text{Min } V_{IH} = (0.88*V_{cc}) \text{ V}$	1.584	1.5841	0.006
$\text{Max } V_{IL} = (0.12*V_{cc}) \text{ V}$	0.216	0.214263	-0.804

High Level and Low Level Input Voltage ($V_{cc} = 5$ V)

Circuit simulation result



Evaluation circuit

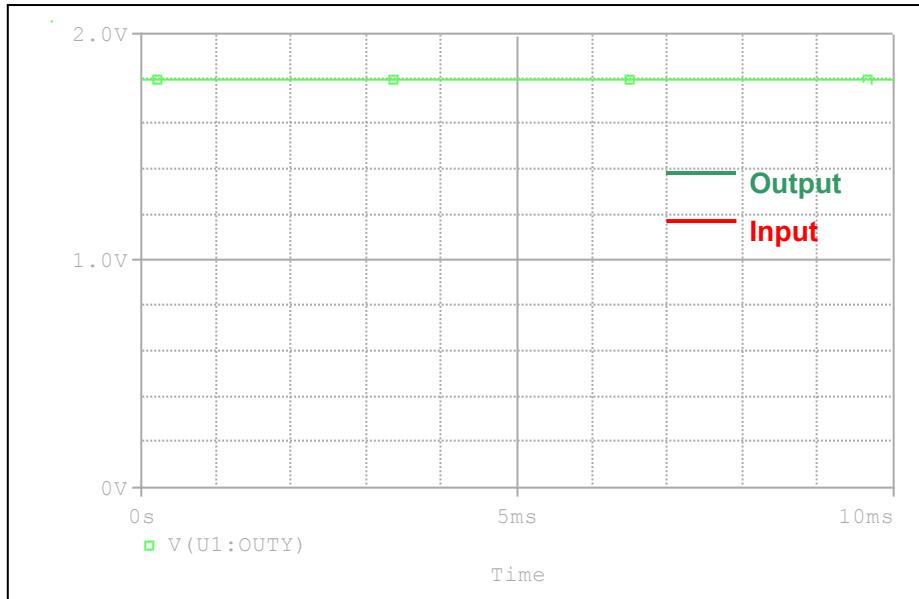


Comparison table

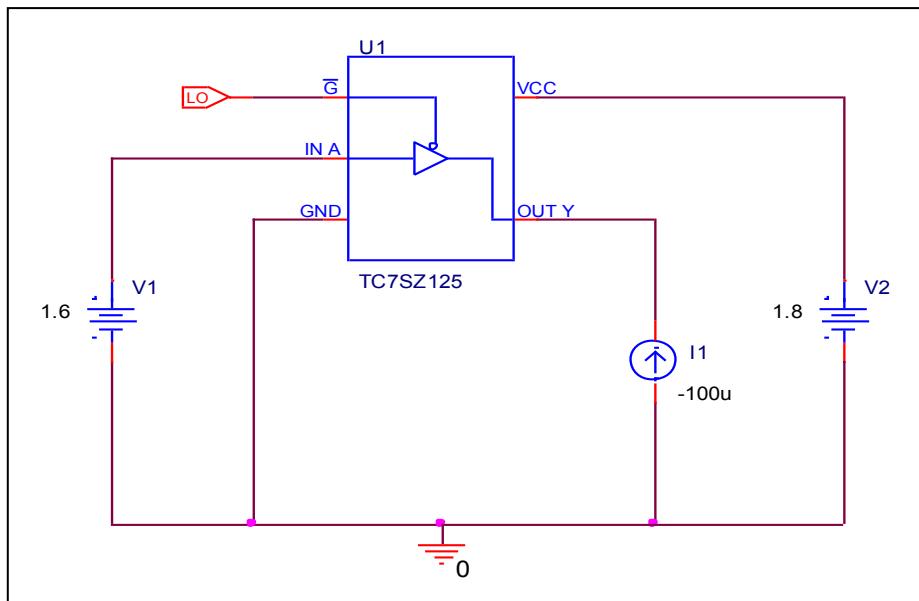
$V_{cc} = 5V$	Measurement	Simulation	%Error
$\text{Min } V_{IH} = (0.75*V_{cc}) \text{ V}$	3.75	3.7501	0.003
$\text{Max } V_{IL} = (0.25*V_{cc}) \text{ V}$	1.25	1.2450	-0.400

High Level Output Voltage ($V_{CC} = 1.8$ V)

Circuit simulation result



Evaluation circuit



Comparison table

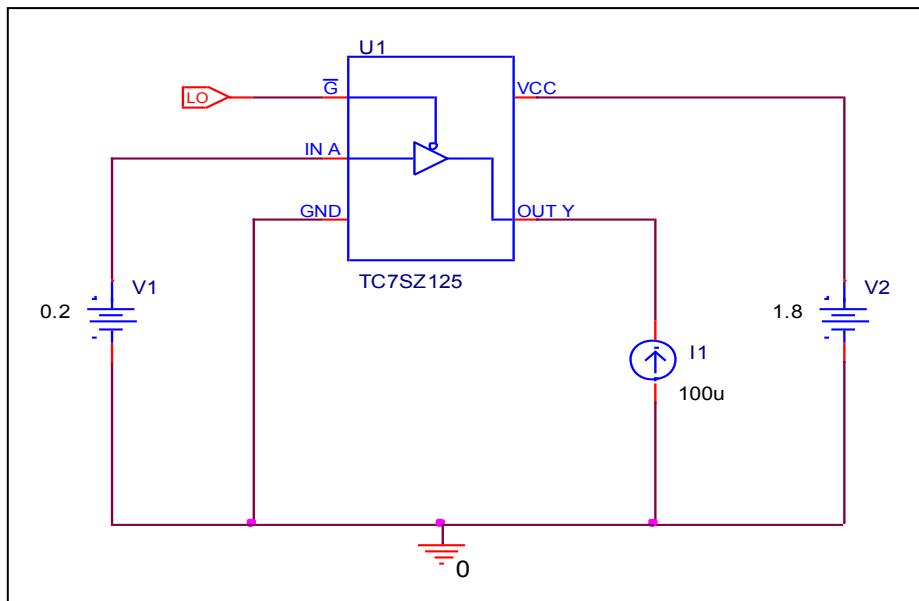
$V_{IN} = V_{IH}$, $V_{CC} = 1.8$ V	Measurement	Simulation	%Error
V_{OH} (V)	1.8	1.7999	-0.006

Low Level Output Voltage ($V_{CC} = 1.8 \text{ V}$)

Circuit simulation result



Evaluation circuit

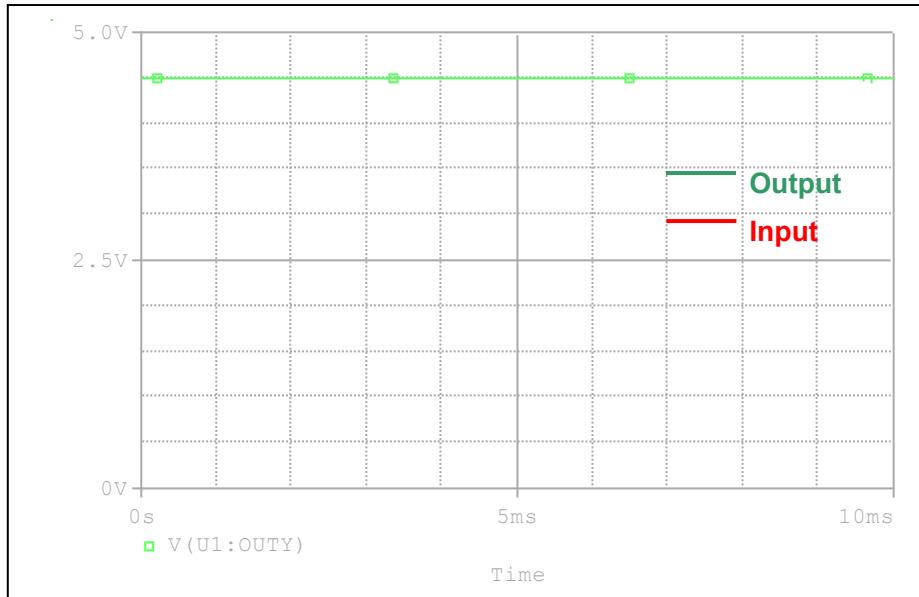


Comparison table

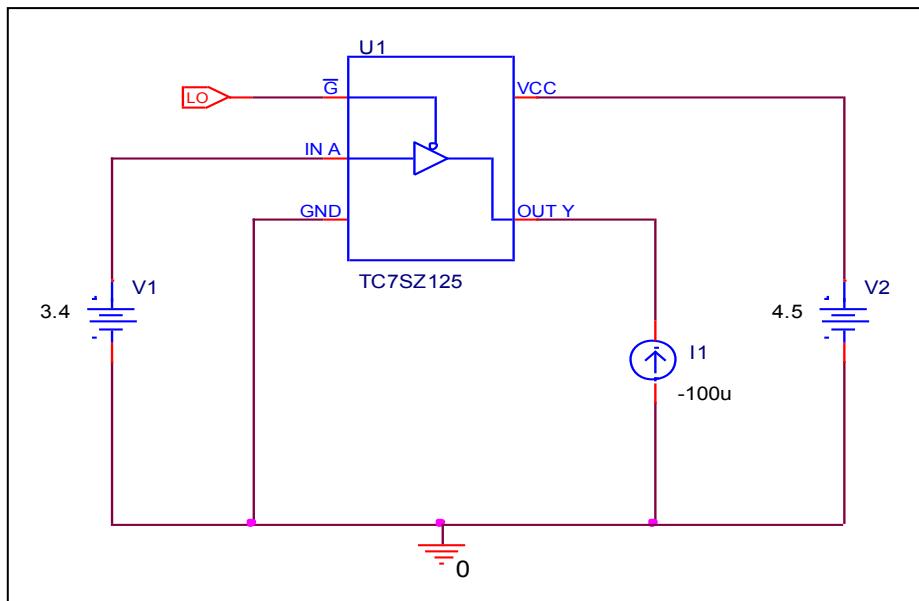
$V_{IN} = V_{IL}, V_{CC} = 4.5 \text{ V}$	Measurement	Simulation	%Error
$V_{OL} (\text{V})$	0	0	0

High Level Output Voltage ($V_{CC} = 4.5$ V)

Circuit simulation result



Evaluation circuit



Comparison table

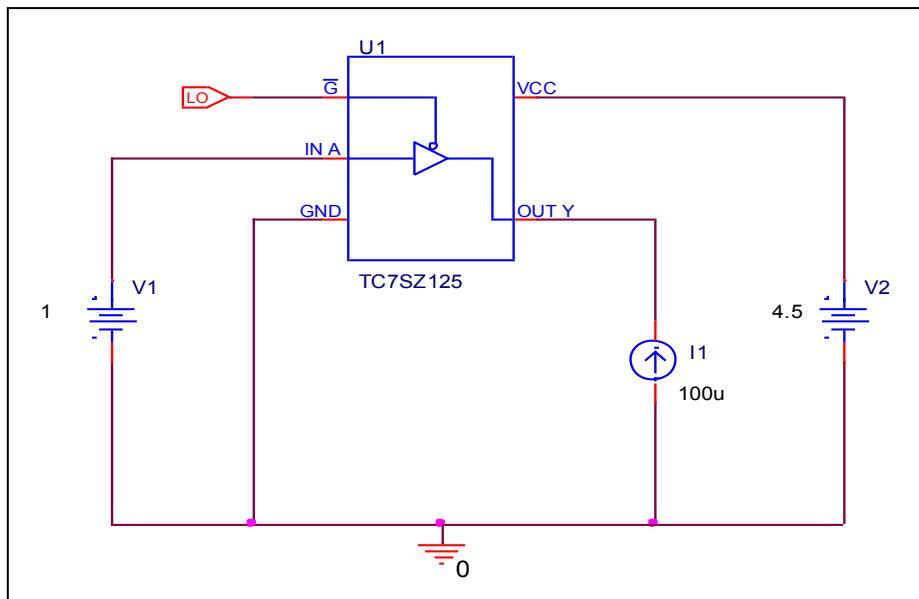
$V_{IN} = V_{IH}$, $V_{CC} = 4.5$ V	Measurement	Simulation	%Error
V_{OH} (V)	4.5	4.4991	-0.02

Low Level Output Voltage ($V_{CC} = 4.5 \text{ V}$)

Circuit simulation result



Evaluation circuit

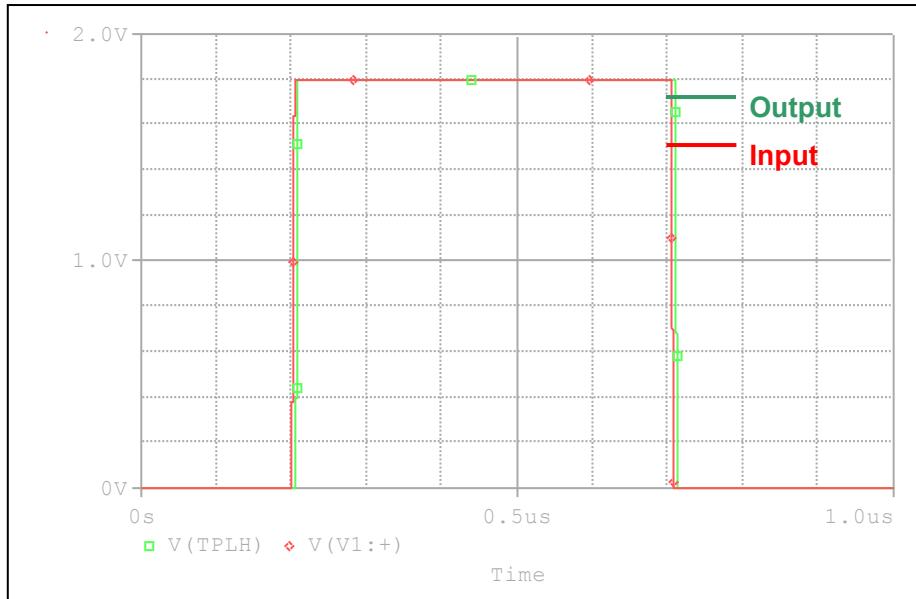


Comparison table

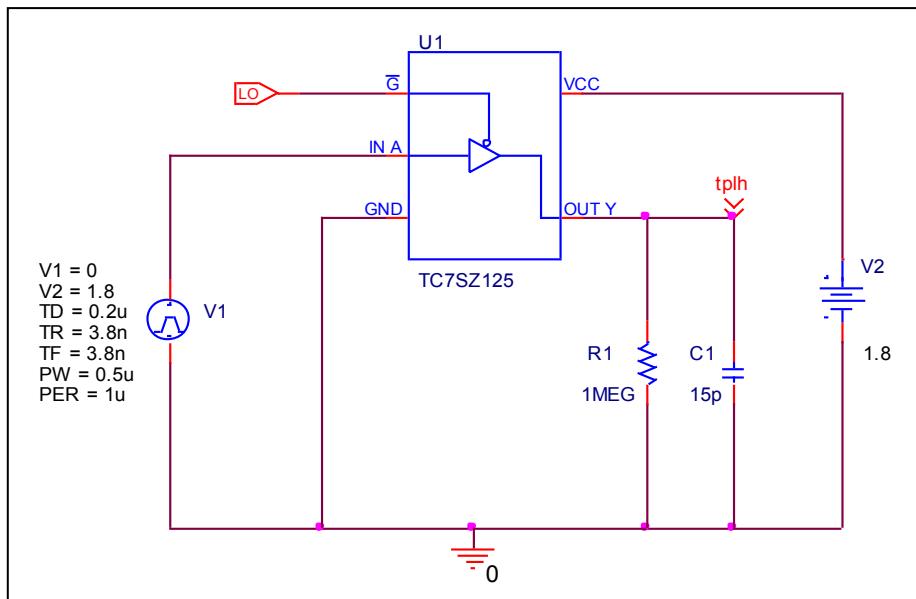
$V_{IN} = V_{IL}, V_{CC} = 4.5 \text{ V}$	Measurement	Simulation	%Error
$V_{OL} (\text{V})$	0	0	0

Propagation Delay Time ($V_{CC} = 1.8$ V)

Circuit simulation result



Evaluation circuit

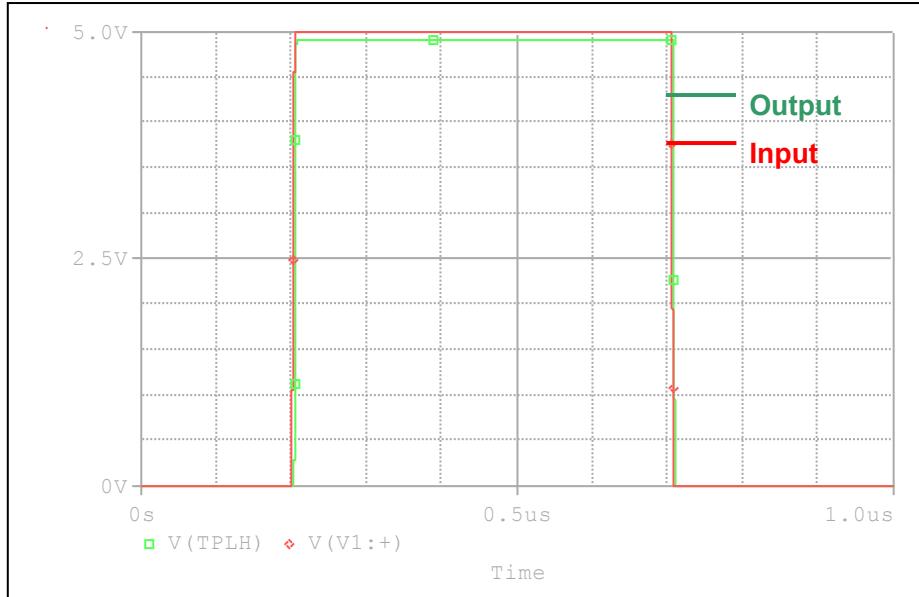


Comparison table $C_L = 15$ pF, $R_L = 1$ M Ω

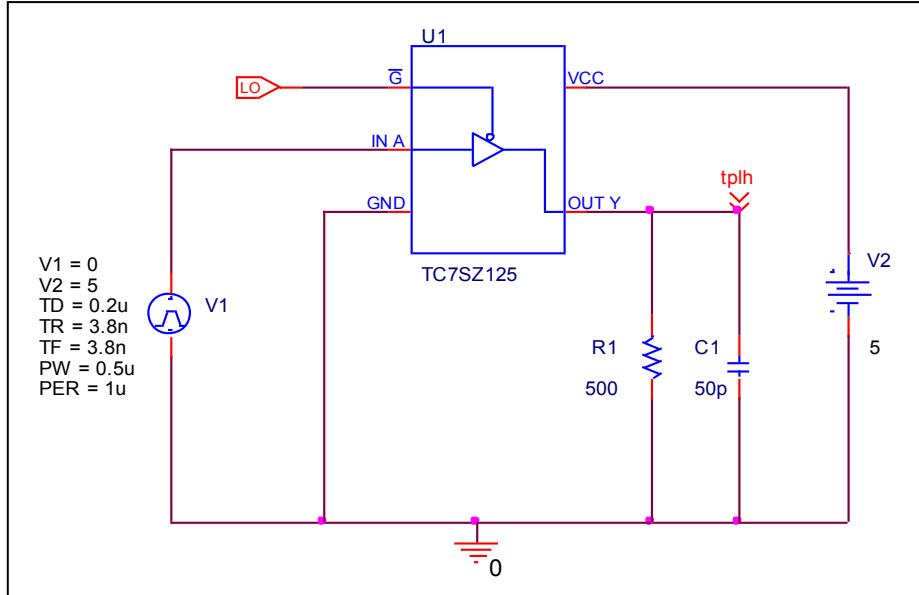
$V_{CC} = 1.8$ V, $t_r = t_f = 3$ ns	Measurement	Simulation	%Error
t_{PLH} (ns)	5.3	5.3208	0.392
t_{PHL} (ns)	5.3	5.3079	0.149

Propagation Delay Time ($V_{cc} = 5$ V)

Circuit simulation result



Evaluation circuit

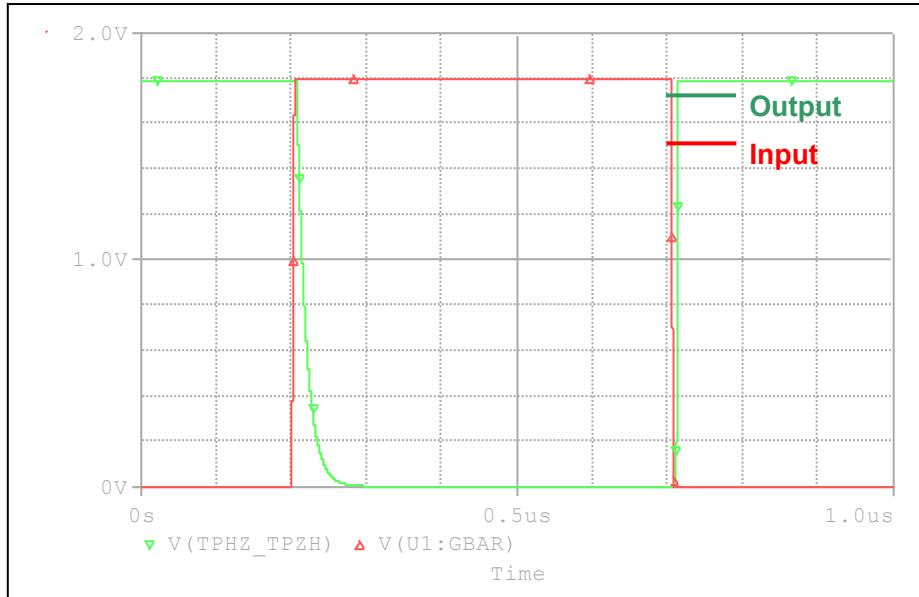


Comparison table $C_L = 50$ pF, $R_L = 500 \Omega$

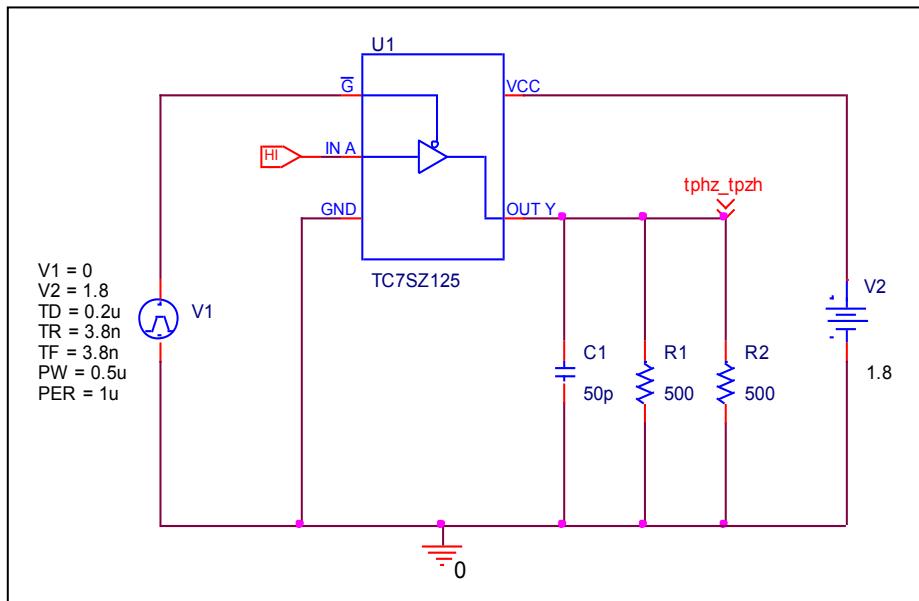
$V_{cc} = 5$ V, $tr = tf = 3$ ns	Measurement	Simulation	%Error
t_{PLH} (ns)	2.6	2.6444	1.708
t_{PHL} (ns)	2.6	2.6279	1.073

Output enable time(t_{PZH}) and Output disable time(t_{PHZ}) ($V_{CC} = 1.8$ V)

Circuit simulation result



Evaluation circuit

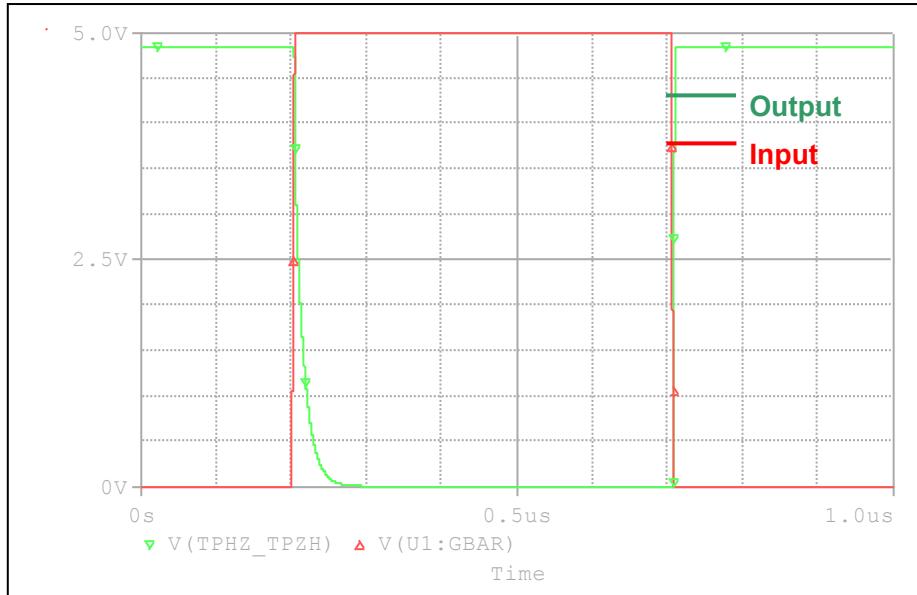


Comparison table $C_L = 50$ pF, $R_L = 500$ Ω

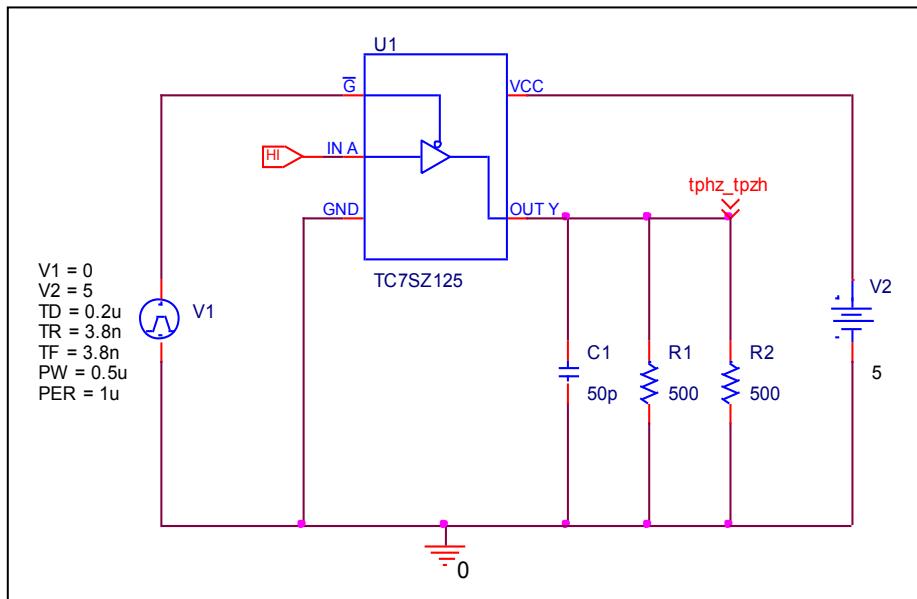
$V_{CC} = 1.8$ V, $t_r = t_f = 3$ ns	Measurement	Simulation	%Error
t_{PZH} (ns)	7	7.0535	0.764
t_{PHZ} (ns)	5.4	5.4334	0.619

Output enable time(t_{PZH}) and Output disable time(t_{PHZ}) ($V_{CC} = 5$ V)

Circuit simulation result



Evaluation circuit

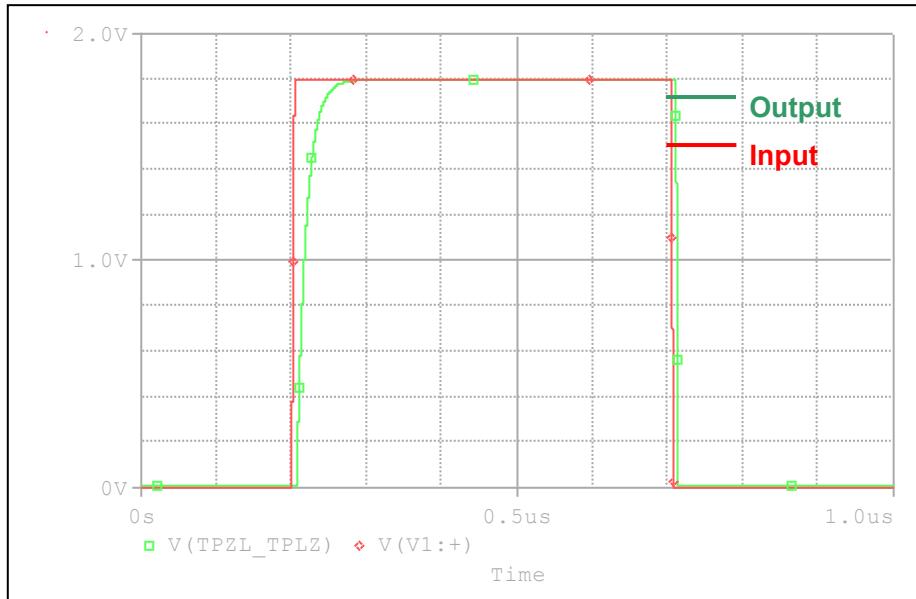


Comparison table $C_L = 50$ pF, $R_L = 500 \Omega$

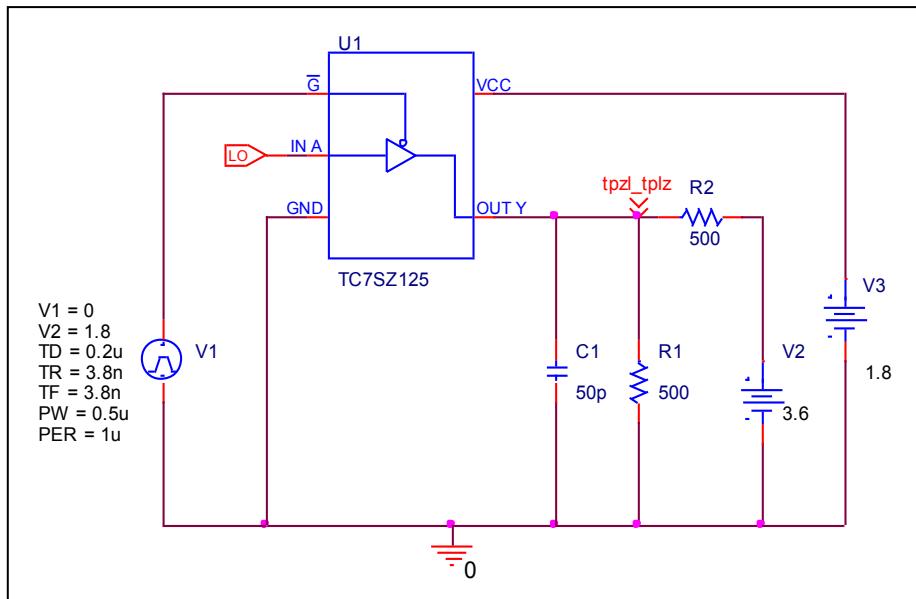
$V_{CC} = 5$ V, $tr = tf = 3$ ns	Measurement	Simulation	%Error
t_{PZH} (ns)	2.8	2.7773	-0.811
t_{PHZ} (ns)	2.1	2.1849	4.043

Output enable time(t_{PZL}) and Output disable time(t_{PLZ}) ($V_{CC} = 1.8$ V)

Circuit simulation result



Evaluation circuit

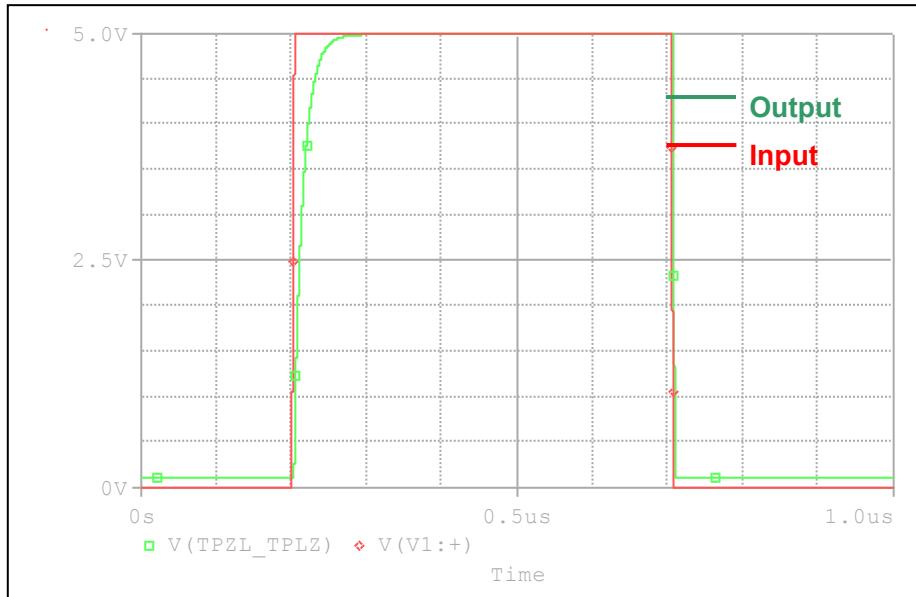


Comparison table $C_L = 50$ pF, $R_L = 500$ Ω

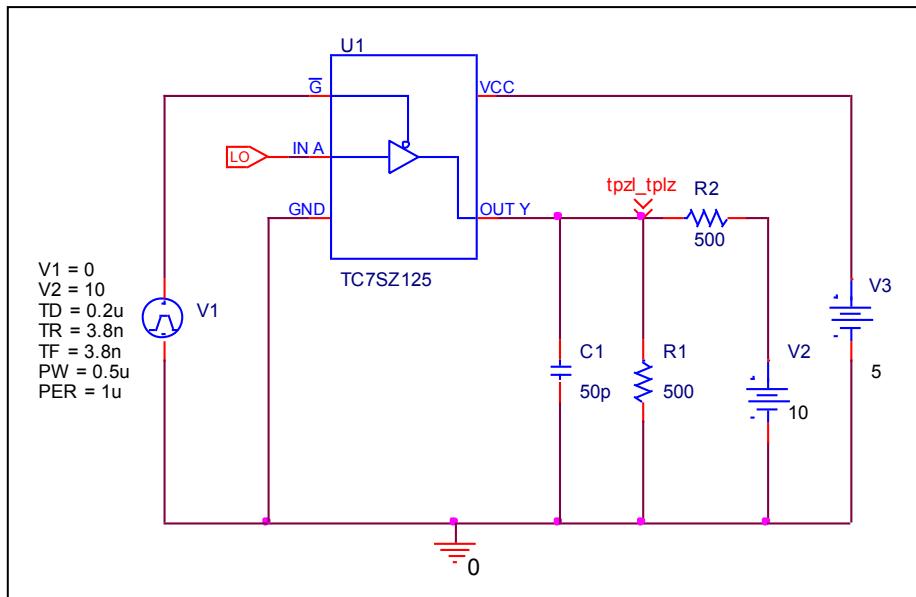
$V_{CC} = 1.8$ V, $tr = tf = 3$ ns	Measurement	Simulation	%Error
t_{PZL} (ns)	7	7.0213	0.304
t_{PLZ} (ns)	5.4	5.4336	0.622

Output enable time(t_{PZL}) and Output disable time(t_{PLZ}) ($V_{CC} = 5$ V)

Circuit simulation result



Evaluation circuit



Comparison table $C_L = 50$ pF, $R_L = 500 \Omega$

$V_{CC} = 5$ V, $tr = tf = 3$ ns	Measurement	Simulation	%Error
t_{PZL} (ns)	2.8	2.7927	-0.261
t_{PLZ} (ns)	2.1	2.1048	0.229